

# Georgios Tsiligiannis

## List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/6690931/publications.pdf>

Version: 2024-02-01

29  
papers

270  
citations

1163117

8  
h-index

996975

15  
g-index

29  
all docs

29  
docs citations

29  
times ranked

440  
citing authors

#	ARTICLE	IF	CITATIONS
1	Multiple Cell Upset Classification  in Commercial SRAMs. IEEE Transactions on Nuclear Science, 2014, 61, 1747-1754.	2.0	46
2	Radiation Effects on Deep Submicrometer SRAM-Based FPGAs Under the CERN Mixed-Field Radiation Environment. IEEE Transactions on Nuclear Science, 2018, 65, 1511-1518.	2.0	30
3	Testing a Commercial MRAM Under Neutron and Alpha Radiation in Dynamic Mode. IEEE Transactions on Nuclear Science, 2013, 60, 2617-2622.	2.0	29
4	Dynamic Test Methods for COTS SRAMs. IEEE Transactions on Nuclear Science, 2014, 61, 3095-3102.	2.0	26
5	An SRAM Based Monitor for Mixed-Field Radiation Environments. IEEE Transactions on Nuclear Science, 2014, 61, 1663-1670.	2.0	15
6	Compositional translation of simulink models into synchronous BIP. , 2010, , .		14
7	Investigation on MCU Clustering Methodologies for Cross-Section Estimation of RAMs. IEEE Transactions on Nuclear Science, 2015, 62, 2620-2626.	2.0	12
8	Single-Event Effects in the Peripheral Circuitry of a Commercial Ferroelectric Random Access Memory. IEEE Transactions on Nuclear Science, 2018, 65, 1708-1714.	2.0	12
9	Investigating the Impact of Radiation-Induced Soft Errors on the Reliability of Approximate Computing Systems. , 2020, , .		12
10	Heavy-Ion Radiation Impact on a 4 Mb FRAM Under Different Test Modes and Conditions. IEEE Transactions on Nuclear Science, 2016, 63, 2010-2015.	2.0	10
11	Evaluation of test algorithms stress effect on SRAMs under neutron radiation. , 2012, , .		8
12	SRAM soft error rate evaluation under atmospheric neutron radiation and PVT variations. , 2013, , .		7
13	SEE on Different Layers of Stacked-SRAMs. IEEE Transactions on Nuclear Science, 2015, 62, 2673-2678.	2.0	7
14	On the correlation between Static Noise Margin and Soft Error Rate evaluated for a 40nm SRAM cell. , 2013, , .		6
15	Evaluating a radiation monitor for mixed-field environments based on SRAM technology. Journal of Instrumentation, 2014, 9, C05052-C05052.	1.2	6
16	Soft errors in commercial off-the-shelf static random access memories. Semiconductor Science and Technology, 2017, 32, 013006.	2.0	6
17	Methodologies for the Statistical Analysis of Memory Response to Radiation. IEEE Transactions on Nuclear Science, 2016, 63, 2122-2128.	2.0	5
18	Analyzing the impact of radiation-induced failures in flash-based APSoC with and without fault tolerance techniques at CERN environment. Microelectronics Reliability, 2017, 76-77, 640-643.	1.7	4

#	ARTICLE	IF	CITATIONS
19	Mechanisms of Electron-Induced Single-Event Upsets in Medical and Experimental Linacs. IEEE Transactions on Nuclear Science, 2018, 65, 1715-1723.	2.0	3
20	A Mixed Verification Strategy Tailored for Networks on Chip. , 2012, , .		2
21	Multiple-Cell-Upsets on a commercial 90nm SRAM in dynamic mode. , 2013, , .		2
22	Reliability Analysis of Ethernet-Based Solutions for Data Transmission in the CERN Radiation Environment. IEEE Transactions on Nuclear Science, 2020, 67, 1614-1622.	2.0	2
23	FPGA Benchmarking Structures Dedicated to TID Parametric Degradation Evaluation. IEEE Transactions on Nuclear Science, 2022, 69, 1453-1460.	2.0	2
24	Characterization of an SRAM based particle detector for mixed-field radiation environments. , 2013, , .		1
25	A Methodology for the Analysis of Memory Response to Radiation through Bitmap Superposition and Slicing. , 2015, , .		1
26	On the evaluation of FPGA radiation benchmarks. Microelectronics Reliability, 2021, 126, 114276.	1.7	1
27	Reliability analysis of a 65nm Rad-Hard SRAM-Based FPGA for CERN applications. , 2019, , .		1
28	SEU monitoring in mixed-field radiation environments of particle accelerators. , 2013, , .		0
29	90Ånm SRAM Static and Dynamic Mode Real-Time Testing at Concordia Station in Antarctica. IEEE Transactions on Nuclear Science, 2014, 61, 3389-3394.	2.0	0